

UVS-2500Miniature Spectrometer

- Emission, Absorbance, Transmittance and Reflectance Spectrometer
- UV-Vis-NIR Detection Wavelength Range from 850-190 nm
- From 1 ms to 4 seconds CCD Integration time
- UV-Enhanced Coated Detector
- Aberration- Corrected Concave Holographic Grating
- High speed USB2- interface
- Miniature size and Weight
- Ruggedized Aluminum Enclosure
- No Need to External Power Supply
- Detachable optics assembly suitable for portable process, and lab applications
- Fiber Optics cables with SMA 905 input fiber connectors for interfacing with other equipment such as light sources
 and sample holders.
- Simultaneous emission meter, Colorimeter and Spectrometer
- UVS2500- can be used as an emission meter for characterize all kinds of light, as a UV-Vis-NIR spectrometer to measure absorbance and a colorimeter to determine the CIE (L*, a*, b*) parameters of visible light.
- It's a modular spectrometer that can acquire a full spectrum in less than 1 millisecond with 0.2 nm resolution.

Applications: Material science Life Science Food Science Earth Science Painting And more...

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	UVS- 2500	
Specifications		
Wavelength range	190 - 850 nm	
Spectral Range	660 nm	
Wavelength accuracy	± 0.1 nm	
Resolution	0.2 nm	
Stray-light	%0.1-0.04 in Absorbance	
Detector	CCD linear array, 3648 pixels	
Signal/Noise	700:1	
Integration time	1 ms -4s	
Interface	USB 2.0 high-speed, 480 Mbps	
Number of scan to Average	0-99 Scan	
Data transfer speed	3.7 ms /scan (USB2)	
Power supply	Default USB power, 350 mA	
Dimensions	15x13x6 cm	
Weight	700 g	
Data Display and Saving	As printable graph, double column ASCI code, EXCEL	





UVS-spec® software

- Free real-time operating software
- Compatible with Windows XP, 8, 7 or 10
- Dark-level correction
- Calculating ratio of two wavelengths intensities

Additional feature:

Trigger mode

Standard features:

- Thermal Smoothing
- Line thickness
- Grid lines
- Plot mode
- Zoom mode
- Overlay mode
- Cursor mode

Color measurement

UVS-spec® software e nables you to determine CIE parameters of light sources or transparent samples.

Time variation and Kinetics

With UVS-spec® software, you could save changes in spectra with time. The total time and time step of saving spectra is tunable.

UV monitoring

In **UVS-spec**® software UVa, UVb, UVc, their ratio and the total irradiance of UV light could be measured according to UV-USA UV-Europe or Solar standards.

Peak find

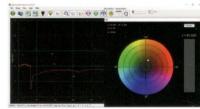
With UVS-spec® software you could find all peaks with a desire width.

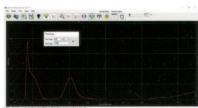
Overlay

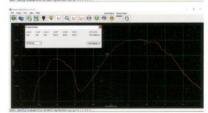
With UVS-spec® software you could monitor the real time changes of spectra.

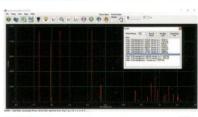
Standard Apps:

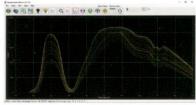
- Wavelength monitoring
- Peak finder
- UV monitoring
- CIE measurements
- Time variation
- Ratio











Contact us:

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Accessories

For miniature spectrometer





Tungsten Halogen Light Source



Deuterium light Source



UV-Vis Optical Fiber



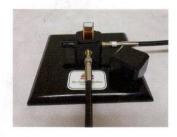
Y-Type Optical Fiber



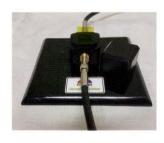
Reflectance Optical Fiber probe



Transmittance Cuvette holder



Photoluminescence
Cuvette holder



Thin Film Sample Holder



White Reflectance Standard

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Modular SpectroChemistry System

Fluorescence and Absorbance

Using -4 side photoluminescence cuvette holder you could measure absorbance straight through the sample and fluorescence at right angles to the excitation light.

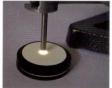




Reflectance and Absorbance

Using reflectance Probe, you could measure normal reflectance and absorbance of the opaque samples.





Thin film transparent measurement

Using slit thin film sample holder, you could measure transmittance and absorbance of thin film supported on transparent substrates



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